



FDU6676AS

N-Channel PowerTrench® SyncFET[™] 30V, 90A, 5.8mΩ

General Description

The FDU6676AS is designed to replace a single MOSFET and Schottky diode in synchronous DC/DC power supplies. This 30V MOSFET is designed to maximize power conversion efficiency, providing a low $R_{\rm DS(ON)}$ and low gate charge. The FDU6676AS includes a patented combination of a MOSFET monolithically integrated with a Schottky diode using Fairchild's monolithic SyncFET technology.

Applications

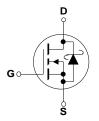
DC/DC converter

Features

- R_{DS(ON)} = 5.8mΩ Max, VGS = 10V
- $R_{DS(ON)} = 7.3 \text{m}\Omega \text{ Max}, VGS = 4.5 \text{V}$
- High performance trench technology for extremely low $R_{\mbox{\scriptsize DS}(\mbox{\scriptsize ON})}$
- · Low Gate Charge
- · High power and current handling capability
- · Includes SyncFET Schottky diode







Absolute Maximum Ratings T_A=25°C unless otherwise noted

| Symbol | Parameter | | Ratings | Units |
|-----------------------------------|--|-----------|-------------|-------|
| V _{DSS} | Drain-Source Voltage | | 30 | V |
| V _{GSS} | Gate-Source Voltage | | ±20 | V |
| I _D | Drain Current -Continuous | (Note 1a) | 90 | А |
| | -Pulsed | | 100 | |
| P _D | Power Dissipation for Single Operation | (Note 1) | 70 | W |
| | | (Note 1a) | 3.1 | |
| | | (Note 1b) | 1.3 | |
| T _J , T _{STG} | Operating and Storage Junction Tempera Range | iture | -55 to +150 | °C |

Thermal Characteristics

| $R_{\theta JC}$ | Thermal Resistance junction to Case | (Note 1) | 1.8 | °C/W |
|-----------------|--|-----------|-----|------|
| $R_{\theta JA}$ | Thermal Resistance junction to Ambient | (Note 1a) | 45 | |
| $R_{	heta JA}$ | Thermal Resistance junction to Ambient | (Note 1b) | 96 | |

Package Marking and Ordering Information

| Device Marking Device | | | | | | |
|-----------------------|-----------|-------------------------|----------------|------------|----------|----|
| | | Package | Reel Size | Tape width | Quantity | |
| | FDU6676AS | FDU6676AS | I-PAK (TO-251) | Tube | N/A | 75 |
| | FDU6676AS | FDU6676AS_F071 (Note 4) | I-PAK (TO-251) | Tube | N/A | 75 |

| Symbol | Parameter | Test Conditions | Min | Тур | Max | Units |
|------------------------------------|---|---|-----|------------|------------|-----------|
| Drain-So | urce Avalanche Ratings (Note | 2) | | | | |
| W _{DSS} | Drain-Source Avalanche Energy | Single Pulse, $V_{DD} = 15V, I_D = 16A$ | | 108 | 250 | mJ |
| I _{AR} | Drain-Source Avalanche Current | | | | 16 | Α |
| Off Chara | acteristics | | | | | |
| | Drain–Source Breakdown | | | | | |
| BV _{DSS} | Voltage | $V_{GS} = 0 \text{ V}, \qquad I_{D} = 250 \mu\text{A}$ | 30 | | | V |
| <u>ΔBVdss</u> ΔT _J | Breakdown Voltage Temperature Coefficient | I _D = 250 μA,Referenced to 25°C | | 29 | | mV/°C |
| I _{DSS} | Zero Gate Voltage Drain Current | V _{DS} = 24 V, V _{GS} = 0 V | | | 500 | μА |
| | , | $V_{DS} = 24 \text{ V}, V_{GS} = 0 \text{ V}, T_J = 125^{\circ}\text{C}$ | | 13 | . 400 | mA |
| I _{GSS} | Gate–Body Leakage | $V_{GS} = \pm 20 \text{ V}, V_{DS} = 0 \text{ V}$ | | | ±100 | nA |
| On Chara | cteristics (Note 2) | | | | | |
| $V_{GS(th)}$ | Gate Threshold Voltage | $V_{DS} = V_{GS}$, $I_D = 250 \mu A$ | 1 | 1.5 | 3 | V |
| $\Delta V_{GS(th)} \ \Delta T_{J}$ | Gate Threshold Voltage Temperature Coefficient | I _D = 250 μA,Referenced to 25°C | | -4 | | mV/°(|
| R _{DS(on)} | Static Drain-Source | $V_{GS} = 10 \text{ V}, I_{D} = 16 \text{ A}$ | | 4.8 | 5.8 | $m\Omega$ |
| | On–Resistance | $V_{GS} = 4.5 \text{ V}, I_D = 10 \text{ A}$ $V_{GS} = 10 \text{ V}, I_D = 16 \text{ A}, T_J = 125 ^{\circ}\text{C}$ | | 5.8 7.7 | 7.3 9.6 | |
| g FS | Forward Transconductance | $V_{DS} = 10 \text{ V}, I_D = 16 \text{ A}$ | | 67 | | S |
| | | 150 10 1, 15 10 1 | 1 | - | | |
| C _{iss} | Characteristics Input Capacitance | 1 | | 2470 | 1 | pF |
| C _{oss} | Output Capacitance | $V_{DS} = 15 \text{ V}, V_{GS} = 0 \text{ V},$ | | 710 | | pF |
| C _{rss} | Reverse Transfer Capacitance | f = 1.0 MHz | | 260 | | pF |
| | Gate Resistance | V _{GS} = 100 mV, f = 1.0 MHz | | 1.8 | | |
| R _G | | V _{GS} = 100 IIIV, 1 = 1.0 IVITZ | | 1.0 | | Ω |
| | g Characteristics (Note 2) | T | 1 | | | |
| t _{d(on)} | Turn-On Delay Time | | | 12 | 22 | ns |
| t _r | Turn-On Rise Time | $V_{DD} = 15 \text{ V}, \qquad I_D = 1 \text{ A},$ | | 12 | 22 | ns |
| t _{d(off)} | Turn–Off Delay Time | $V_{GS} = 10 \text{ V}, \qquad R_{GEN} = 6 \Omega$ | | 50 | 80 | ns |
| t _f | Turn–Off Fall Time | | | 25 | 40 | ns |
| t _{d(on)} | Turn-On Delay Time | _ | | 20 | 32 | ns |
| t _r | Turn-On Rise Time | $V_{DD} = 15 \text{ V}, \qquad I_D = 1 \text{ A},$ | | 24 | 38 | ns |
| $t_{\text{d(off)}}$ | Turn-Off Delay Time | V_{GS} = 4.5 V, R_{GEN} = 6 Ω | | 34 | 54 | ns |
| t _f | Turn–Off Fall Time | | | 26 | 42 | ns |
| Qg | Total Gate Charge, V _{GS} = 10V | | | 46 | 64 | nC |
| Q _g | Total Gate Charge, V _{GS} = 5V | $V_{DS} = 15V$, $I_{D} = 16 A$ | | 25 | 35 | nC |
| Q _{gs} | Gate–Source Charge | | | 6 | | nC |
| Q_{gd} | Gate-Drain Charge | | | 7 | | nC |

Electrical Characteristics

T_A = 25°C unless otherwise noted

| Symbol | Parameter | Test Conditions | Min | Тур | Max | Units |
|--|------------------------------------|--|-----|-----|-----|-------|
| Drain-Source Diode Characteristics and Maximum Ratings | | | | | | |
| Is | Maximum Continuous Drain-Source | ce Diode Forward Current | | | 2.3 | Α |
| V _{SD} | Drain–Source Diode Forward Voltage | V _{GS} = 0 V, I _S = 2.3 A (Note 2) | | 0.4 | 1.2 | V |
| t _{rr} | Diode Reverse Recovery Time | $I_F = 16 \text{ A}, dI_F/dt = 100 \text{ A/}\mu\text{s}$ | | 28 | | ns |
| Q _{rr} | Diode Reverse Recovery Charge | | | 19 | | nC |

Notes

1. R_{0JA} is the sum of the junction-to-case and case-to-ambient thermal resistance where the case thermal reference is defined as the solder mounting surface of the drain pins. R_{0JC} is guaranteed by design while R_{0CA} is determined by the user's board design.



a) $R_{\theta JA} = 45$ °C/W when mounted on a $1 in^2$ pad of 2 oz copper



b) $R_{\theta JA} = 96^{\circ} \text{C/W}$ when mounted on a minimum pad.

Scale 1:1 on letter size paper

2. Pulse Test: Pulse Width < 300µs, Duty Cycle < 2.0%

3. Maximum current is calculated as: $\sqrt{\frac{P_D}{R_{DS(0)}}}$

where P_D is maximum power dissipation at $T_C = 25^{\circ}C$ and $R_{DS(on)}$ is at $T_{J(max)}$ and $V_{GS} = 10V$. Package current limitation is 21A

4. FDU6676AS_F071 is a lead free product. The FDU6676AS_F071 marking will appear on the reel label.

Typical Characteristics

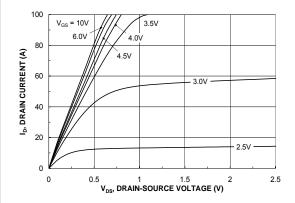


Figure 1. On-Region Characteristics

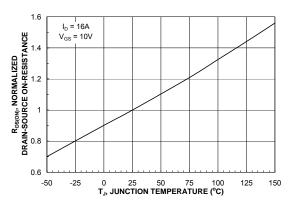


Figure 3. On-Resistance Variation with Temperature

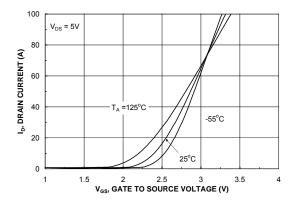


Figure 5. Transfer Characteristics

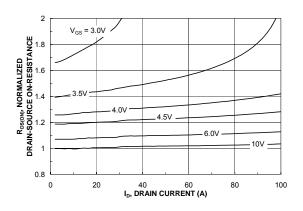


Figure 2. On-Resistance Variation with Drain Current and Gate Voltage

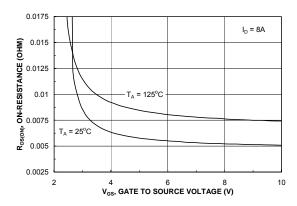


Figure 4. On-Resistance Variation with Gate-to-Source Voltage

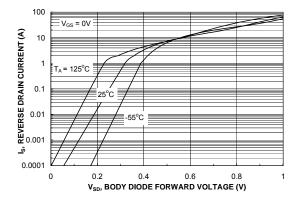
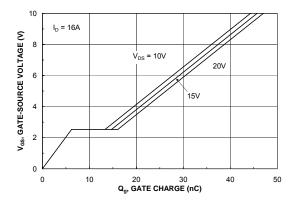


Figure 6. Body Diode Forward Voltage Variation with Source Current and Temperature

Typical Characteristics



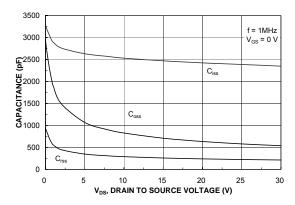
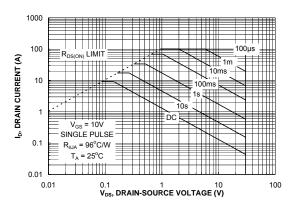


Figure 7. Gate Charge Characteristics





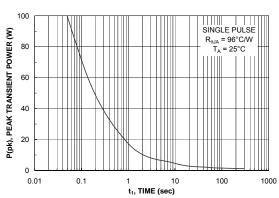


Figure 9. Maximum Safe Operating Area

Figure 10. Single Pulse Maximum Power Dissipation

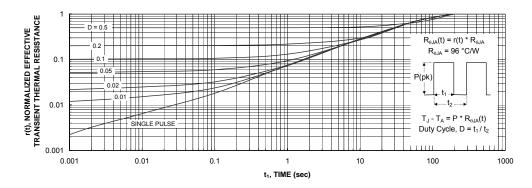


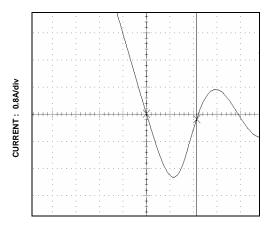
Figure 11. Transient Thermal Response Curve

Thermal characterization performed using the conditions described in Note 1b. Transient thermal response will change depending on the circuit board design.

Typical Characteristics (continued)

SyncFET Schottky Body Diode Characteristics

Fairchild's SyncFET process embeds a Schottky diode in parallel with PowerTrench MOSFET. This diode exhibits similar characteristics to a discrete external Schottky diode in parallel with a MOSFET. Figure 12 shows the reverse recovery characteristic of the FDU6676AS.



TIME: 12.5ns/div

Figure 12. FDU6676AS SyncFET Body Diode Reverse Recovery Characteristic.

For comparison purposes, Figure 13 shows the reverse recovery characteristics of the body diode of an equivalent size MOSFET produced without SyncFET (FDU6676A).

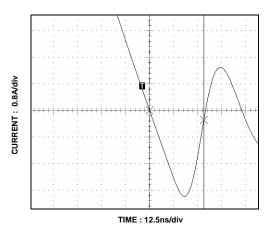


Figure 13. Non-SyncFET (FDU6676A) Body Biode Reverse Recovery Characteristic.

Schottky barrier diodes exhibit significant leakage at high temperature and high reverse voltage. This will increase the power in the device.

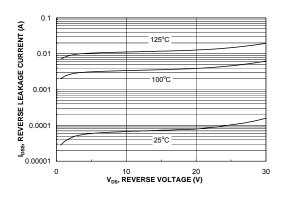


Figure 14. SyncFET Body Diode Reverse Leakage Versus Drain-Source Voltage and Temperature.





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